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METHOD AND SYSTEM FOR IDENTIFYING AND
LOCATING DEFECTS IN AN INTEGRATED CIRCUIT

Inventor: James Francis Plusquellic

Docket No.: P 1087.14002

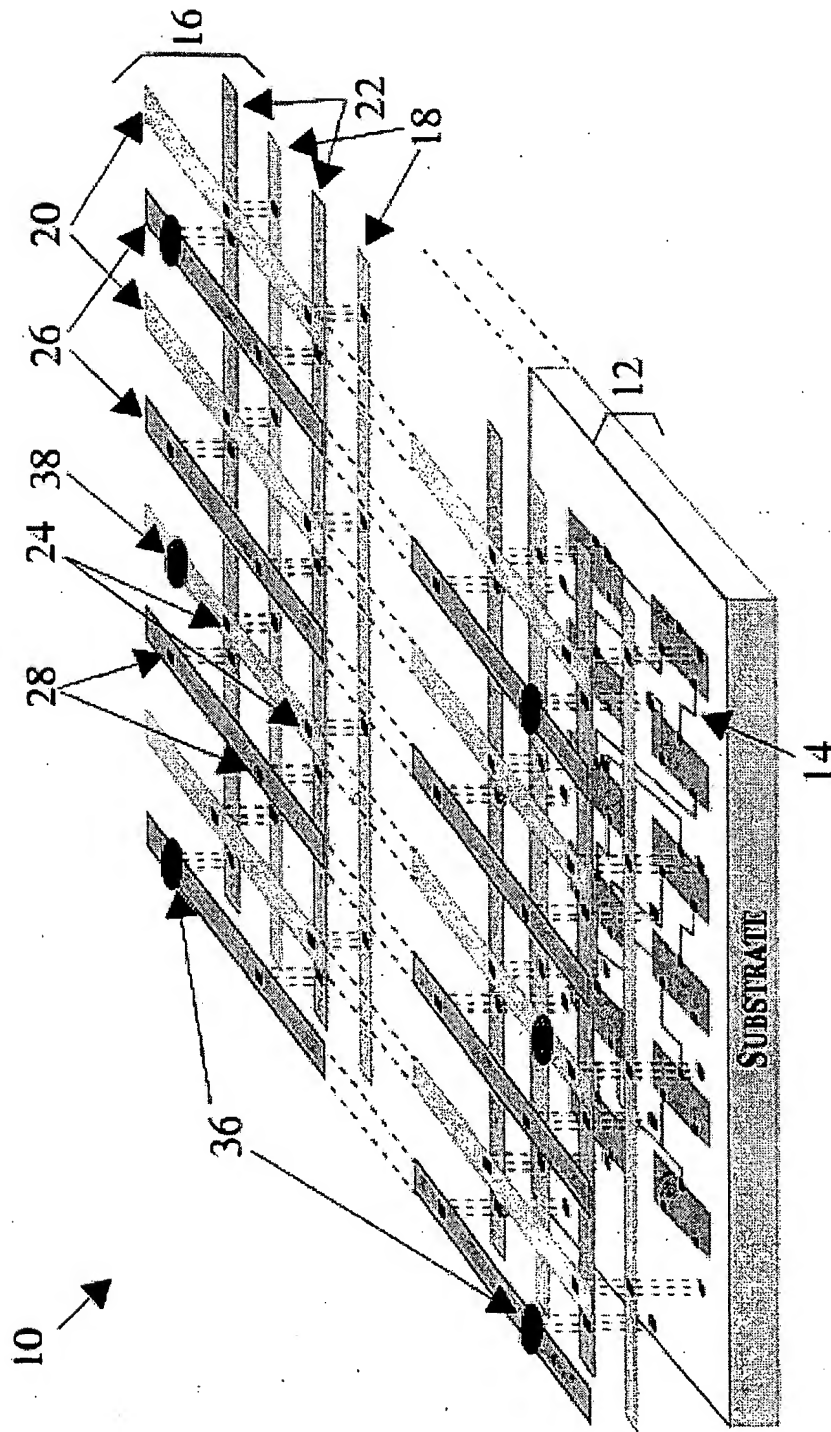


Figure 1

METHOD AND SYSTEM FOR IDENTIFYING AND
LOCATING DEFECTS IN AN INTEGRATED CIRCUIT

Inventor: James Francis Plusquellic

Docket No.: P 1087.14002

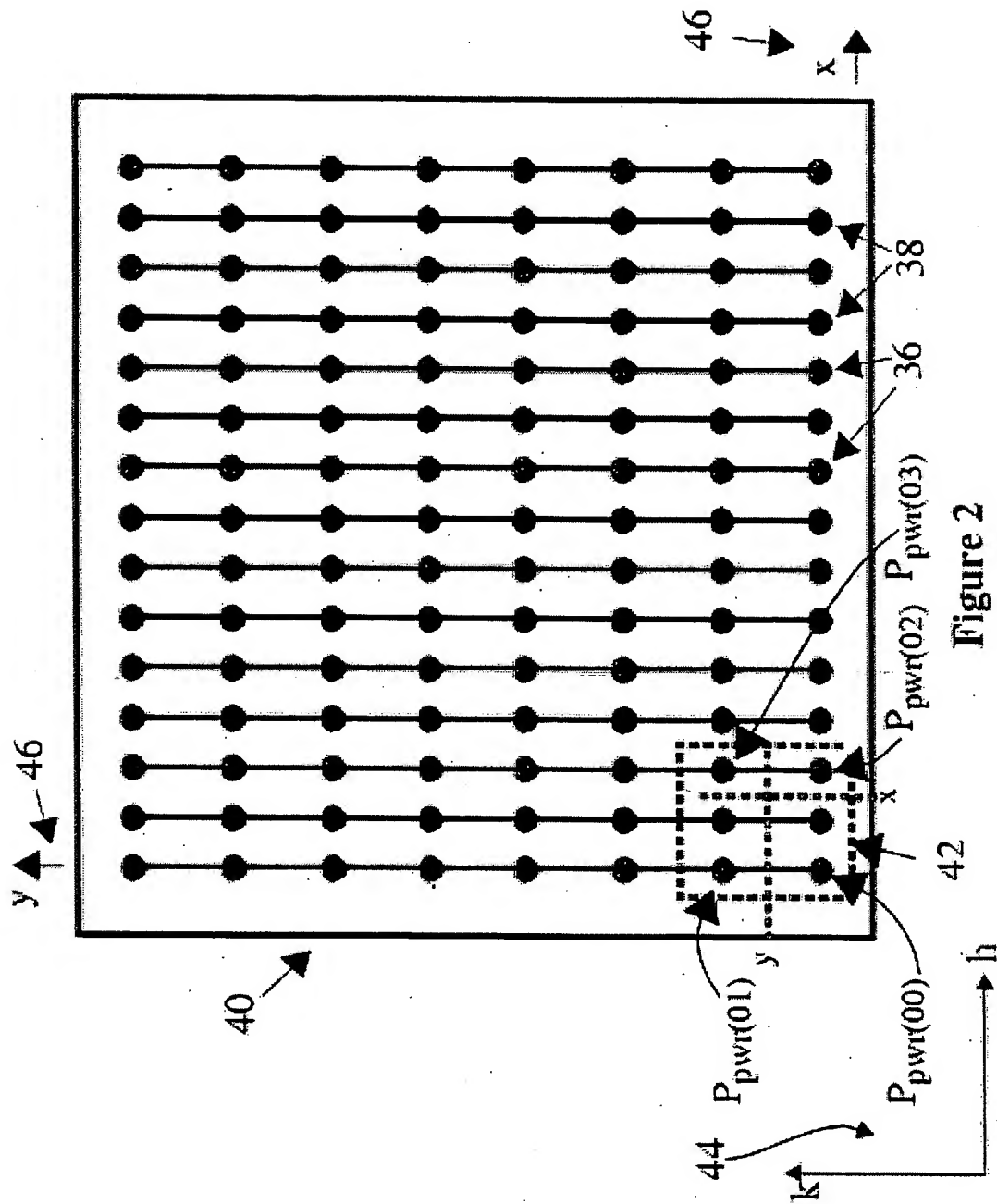


Figure 2

METHOD AND SYSTEM FOR IDENTIFYING AND
LOCATING DEFECTS IN AN INTEGRATED CIRCUIT

Inventor: James Francis Plusquellic

Docket No.: P 1087.14002

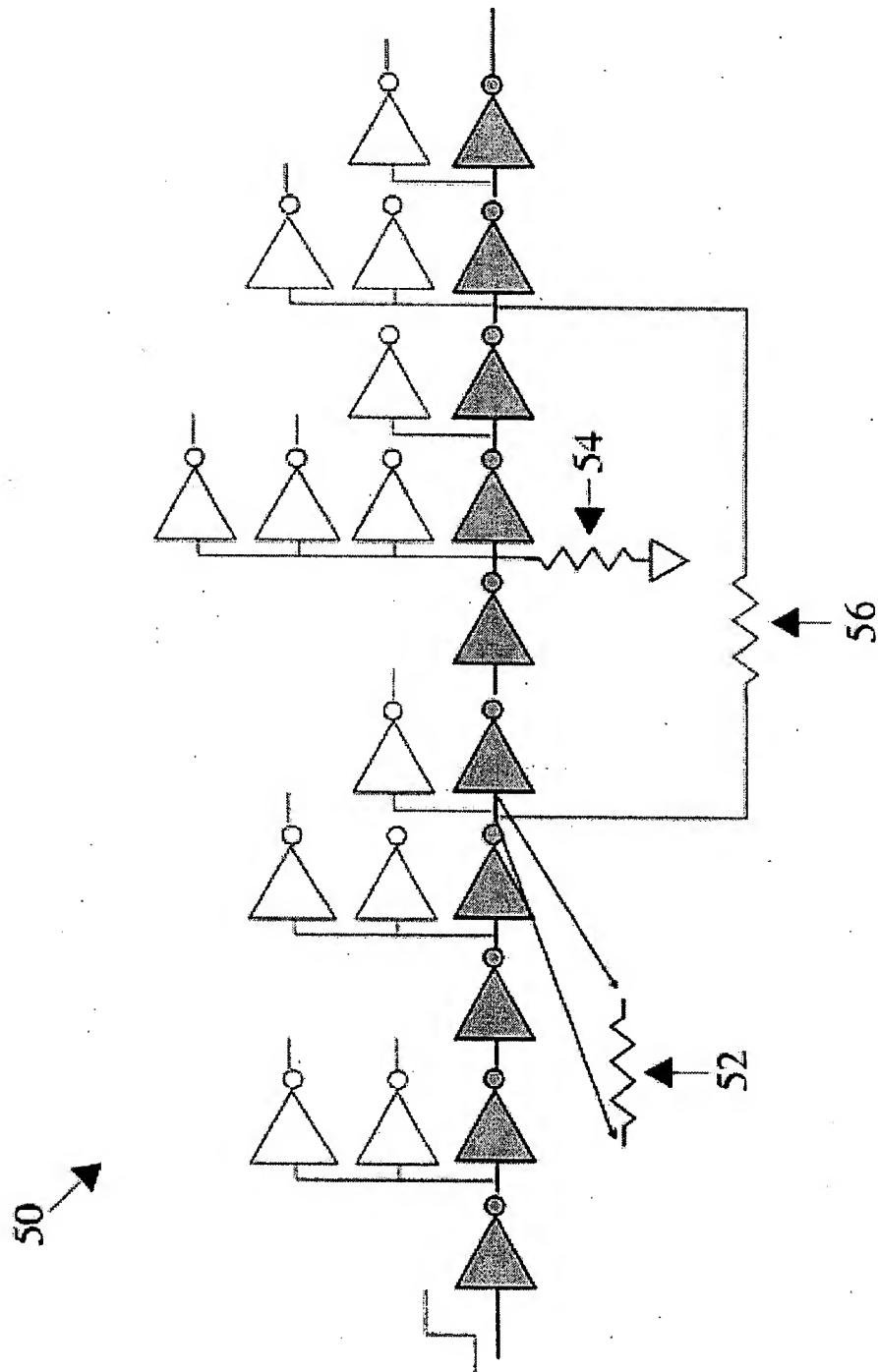


Figure 3

METHOD AND SYSTEM FOR IDENTIFYING AND
LOCATING DEFECTS IN AN INTEGRATED CIRCUIT

Inventor: James Francis Plusquellic

Docket No.: P 1087.14002

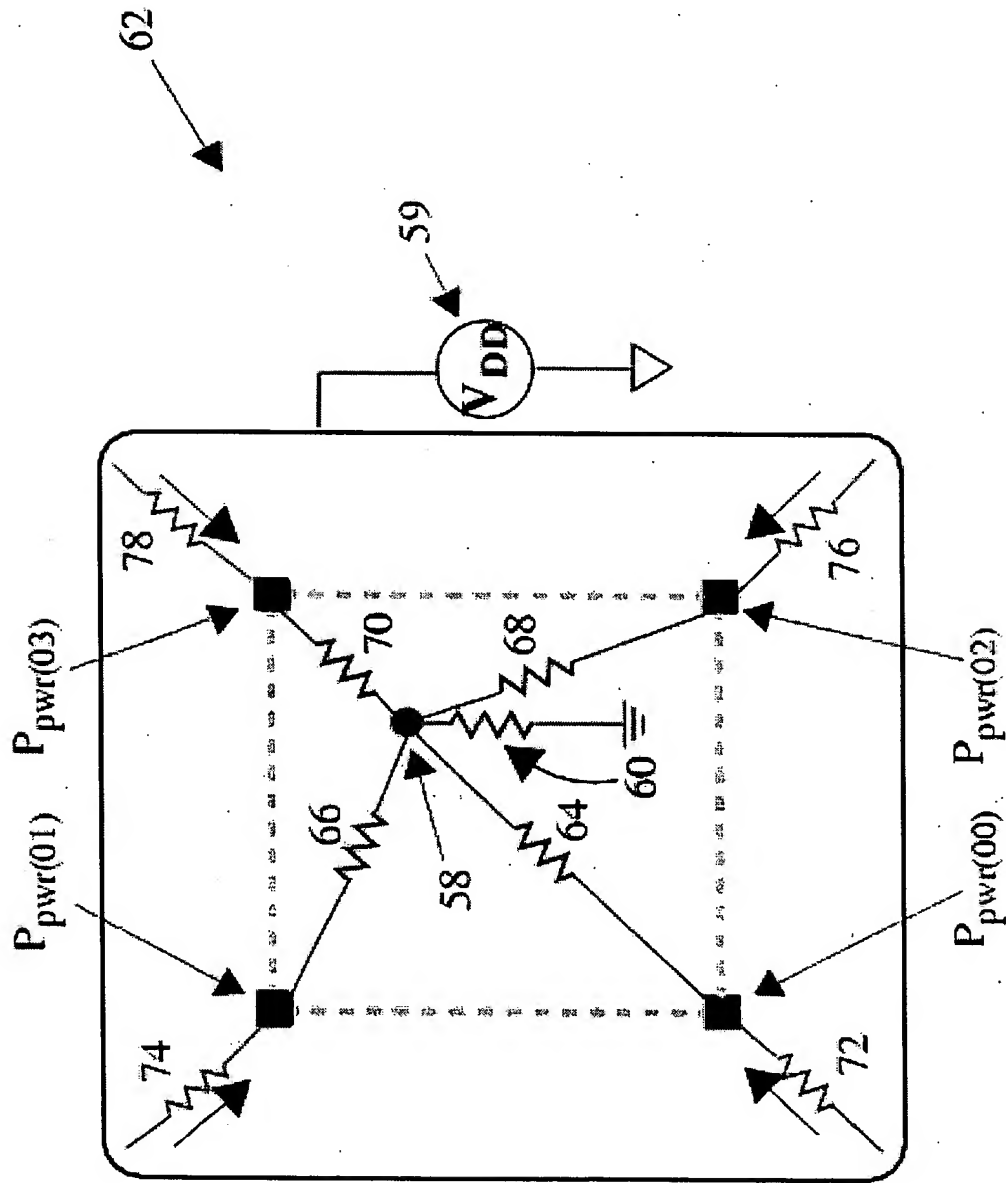


Figure 4

METHOD AND SYSTEM FOR IDENTIFYING AND
LOCATING DEFECTS IN AN INTEGRATED CIRCUIT

Inventor: James Francis Plusquellic

Docket No.: P 1087.14002

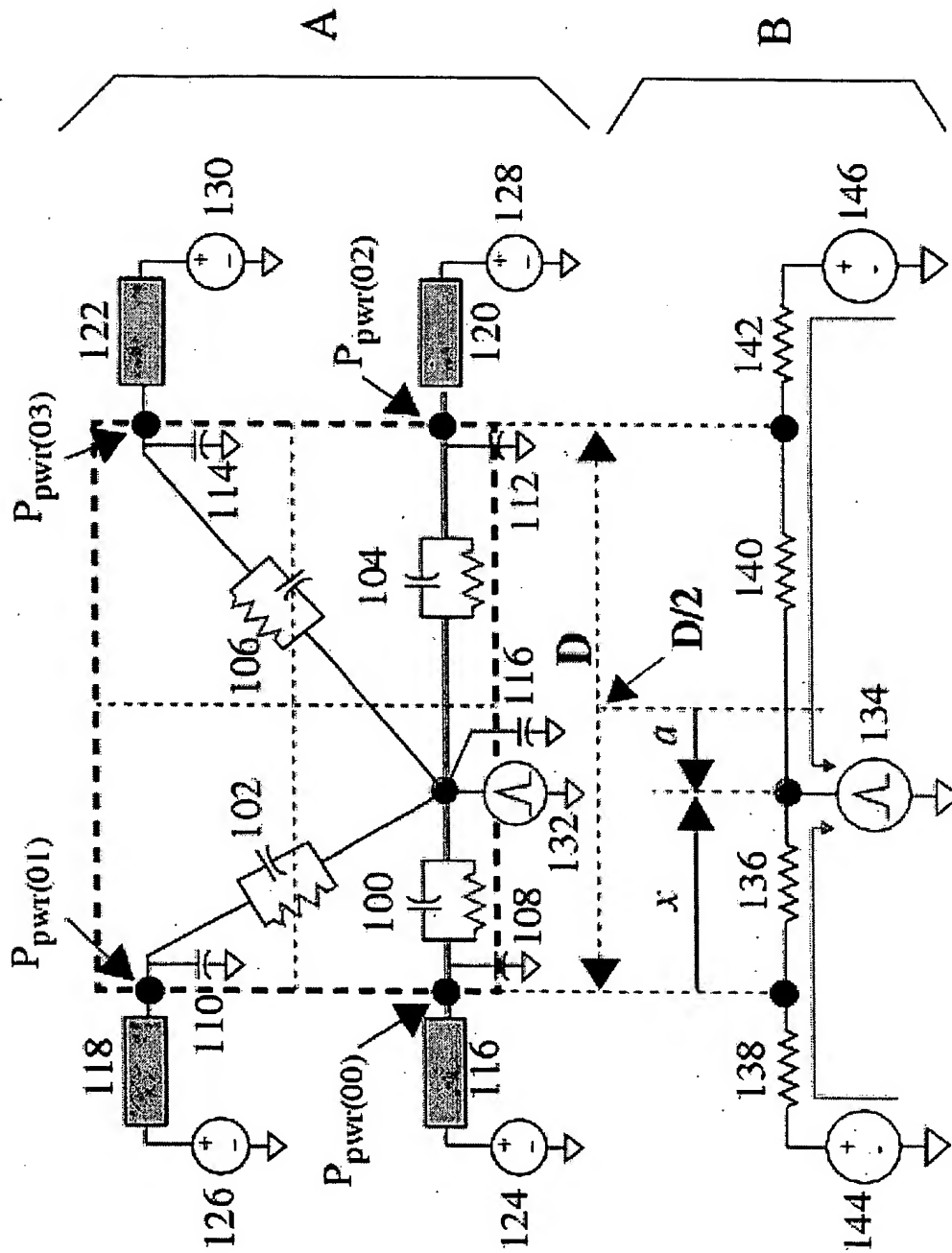


Figure 5

METHOD AND SYSTEM FOR IDENTIFYING AND
LOCATING DEFECTS IN AN INTEGRATED CIRCUIT

Inventor: James Francis Plusquellic

Docket No.: P 1087.14002

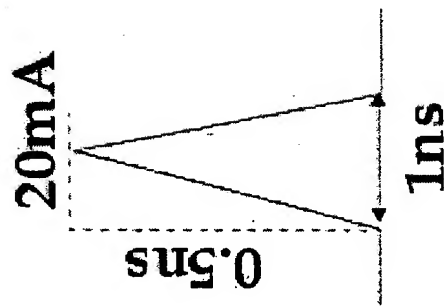


Figure 6

METHOD AND SYSTEM FOR IDENTIFYING AND LOCATING DEFECTS IN AN INTEGRATED CIRCUIT

Inventor: James Francis Plusquellic

Docket No.: P 1087.14002

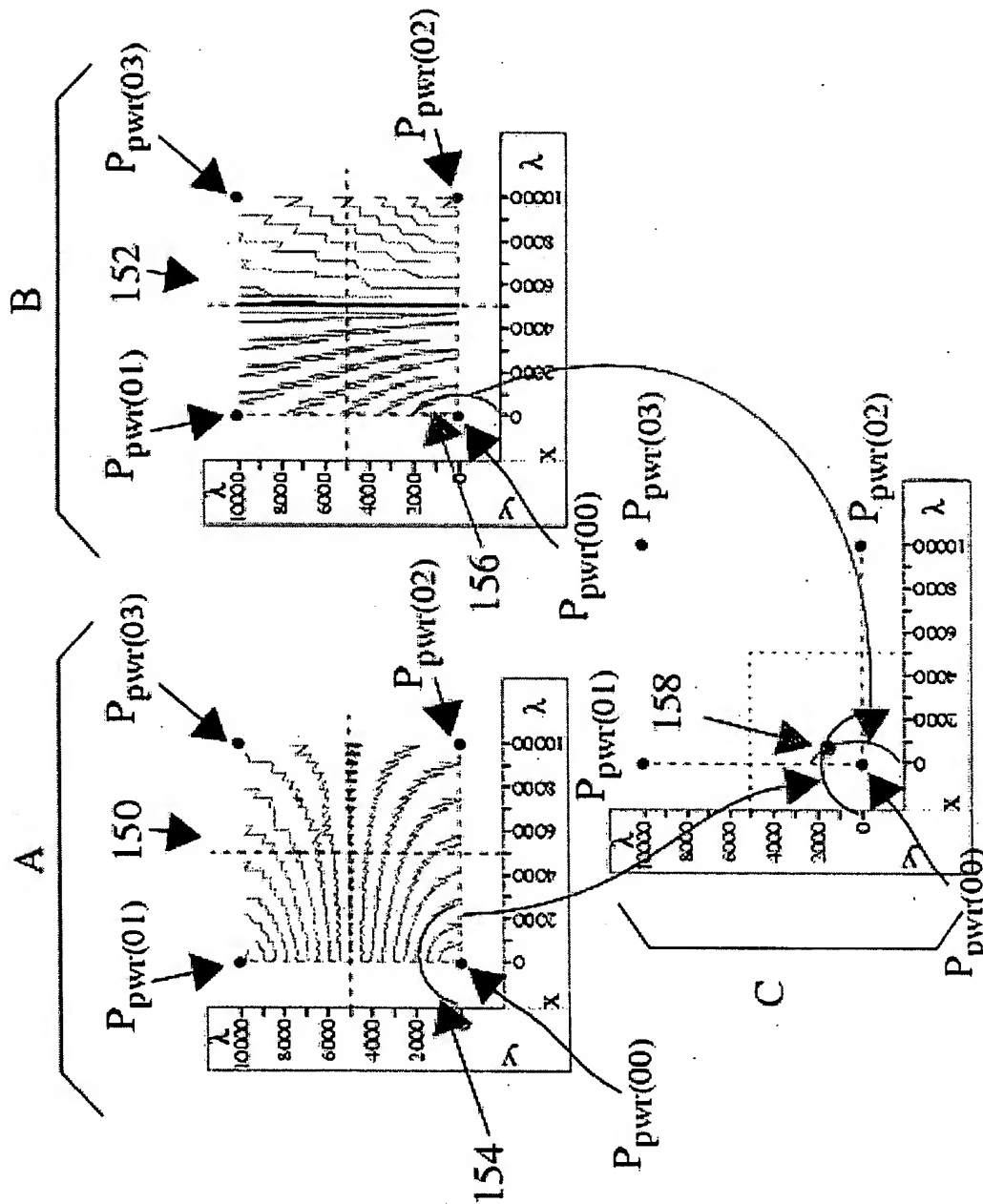


Figure 7

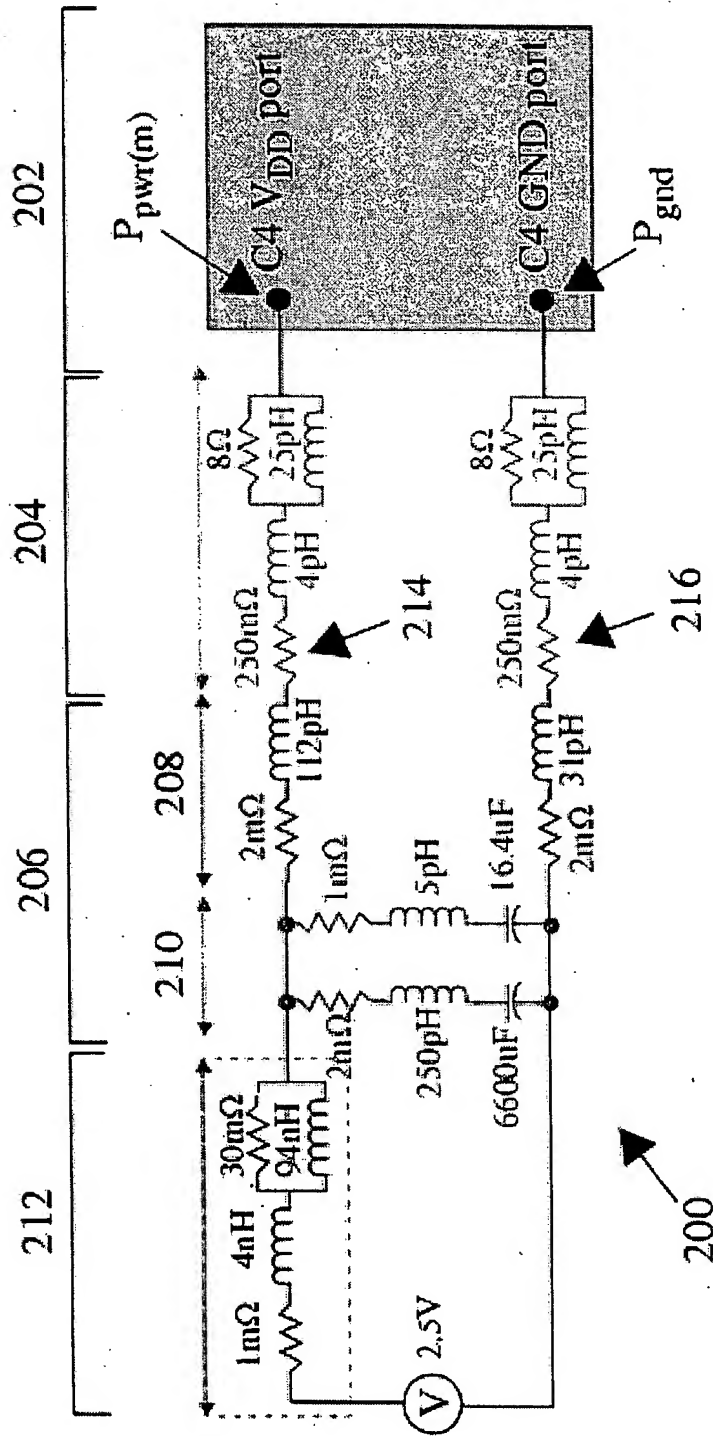


Figure 8

Docket No.: P 1087.14002



METHOD AND SYSTEM FOR IDENTIFYING AND
LOCATING DEFECTS IN AN INTEGRATED CIRCUIT

Inventor: James Francis Plusquellic

Docket No.: P 1087.14002

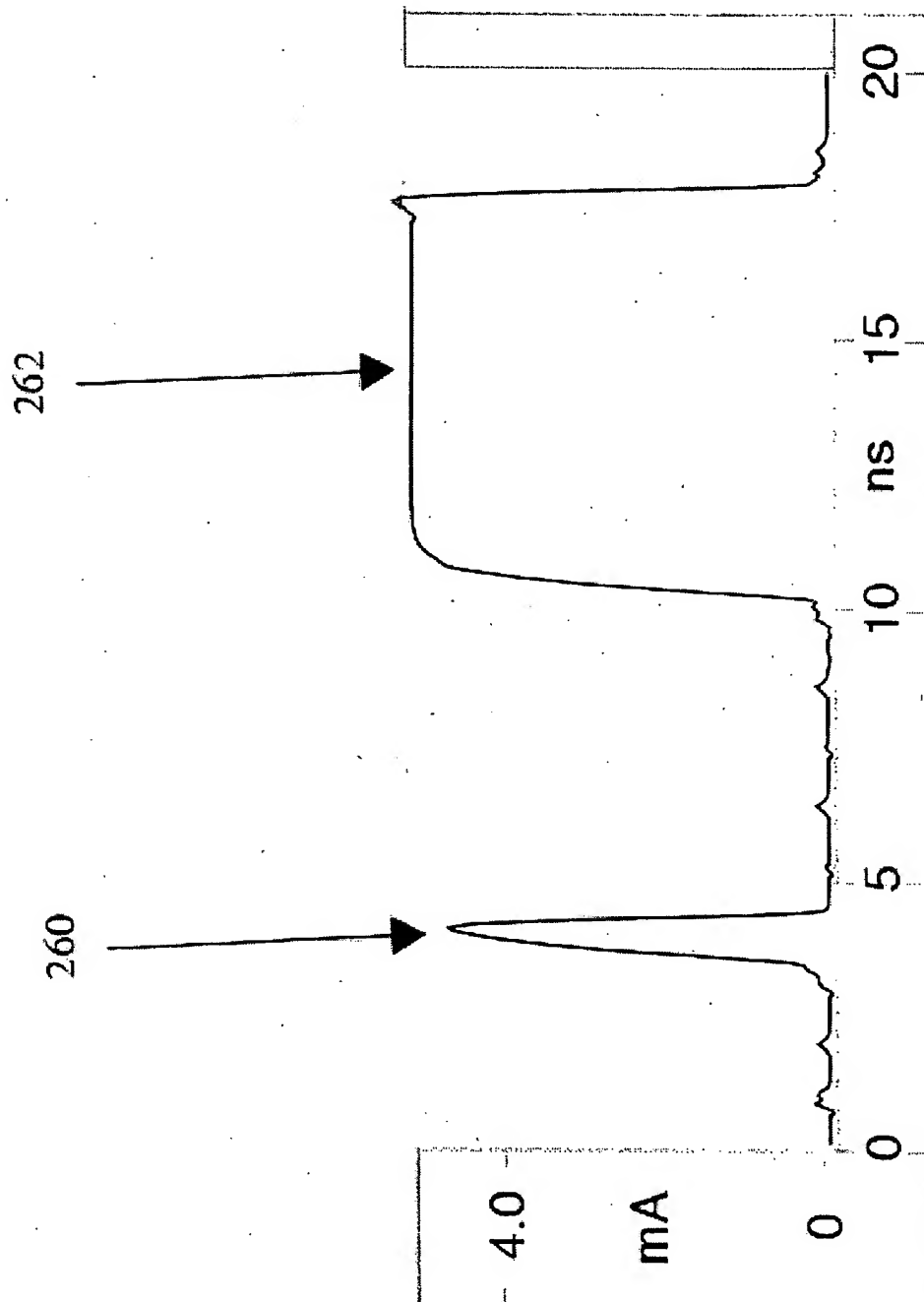


Figure 10

METHOD AND SYSTEM FOR IDENTIFYING AND LOCATING DEFECTS IN AN INTEGRATED CIRCUIT

Inventor: James Francis Plusquellic

Docket No.: P 1087.14002

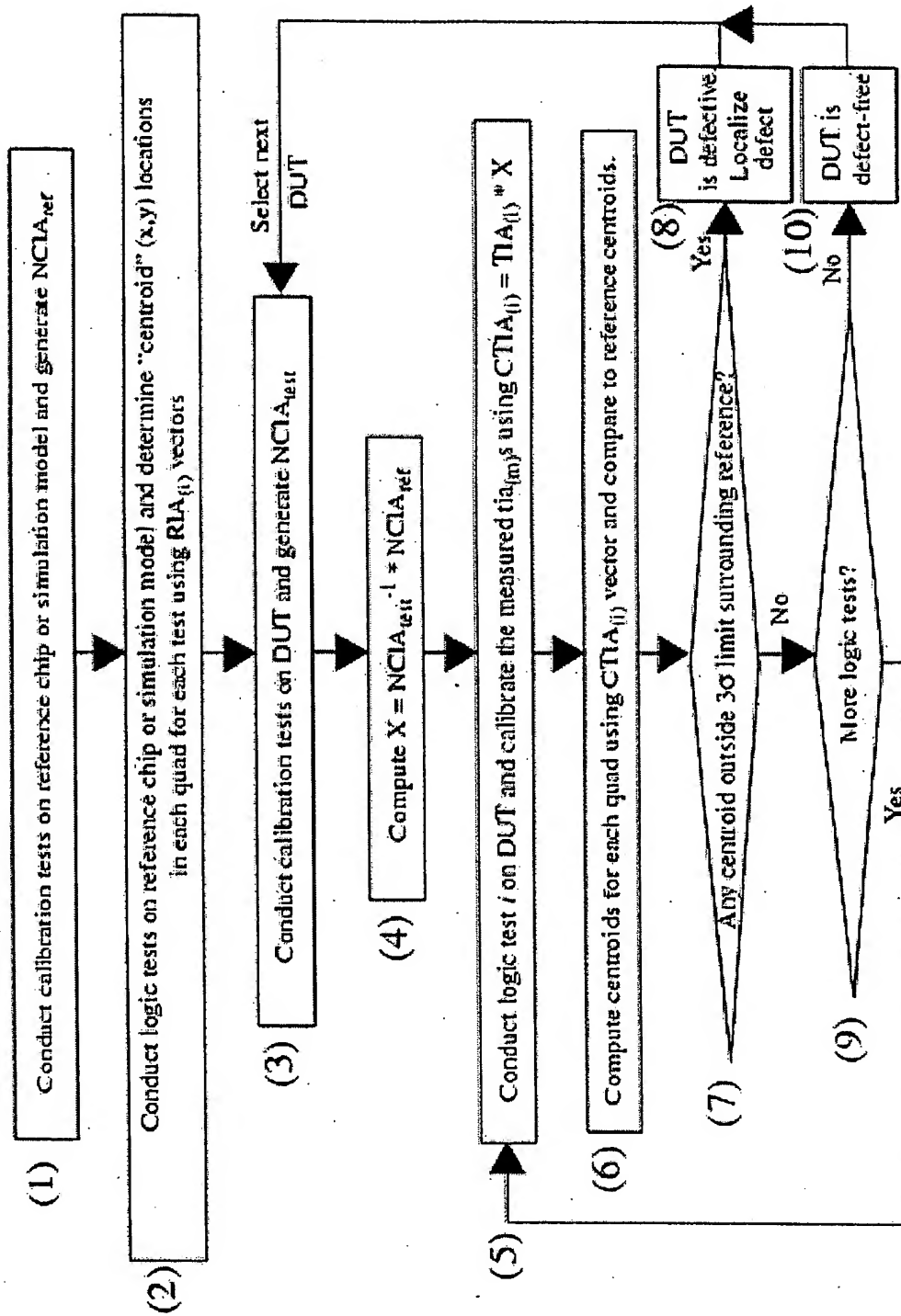


Figure 11

METHOD AND SYSTEM FOR IDENTIFYING AND LOCATING DEFECTS IN AN INTEGRATED CIRCUIT

Inventor: James Francis Plusquellic

Docket No.: P 1087.14002

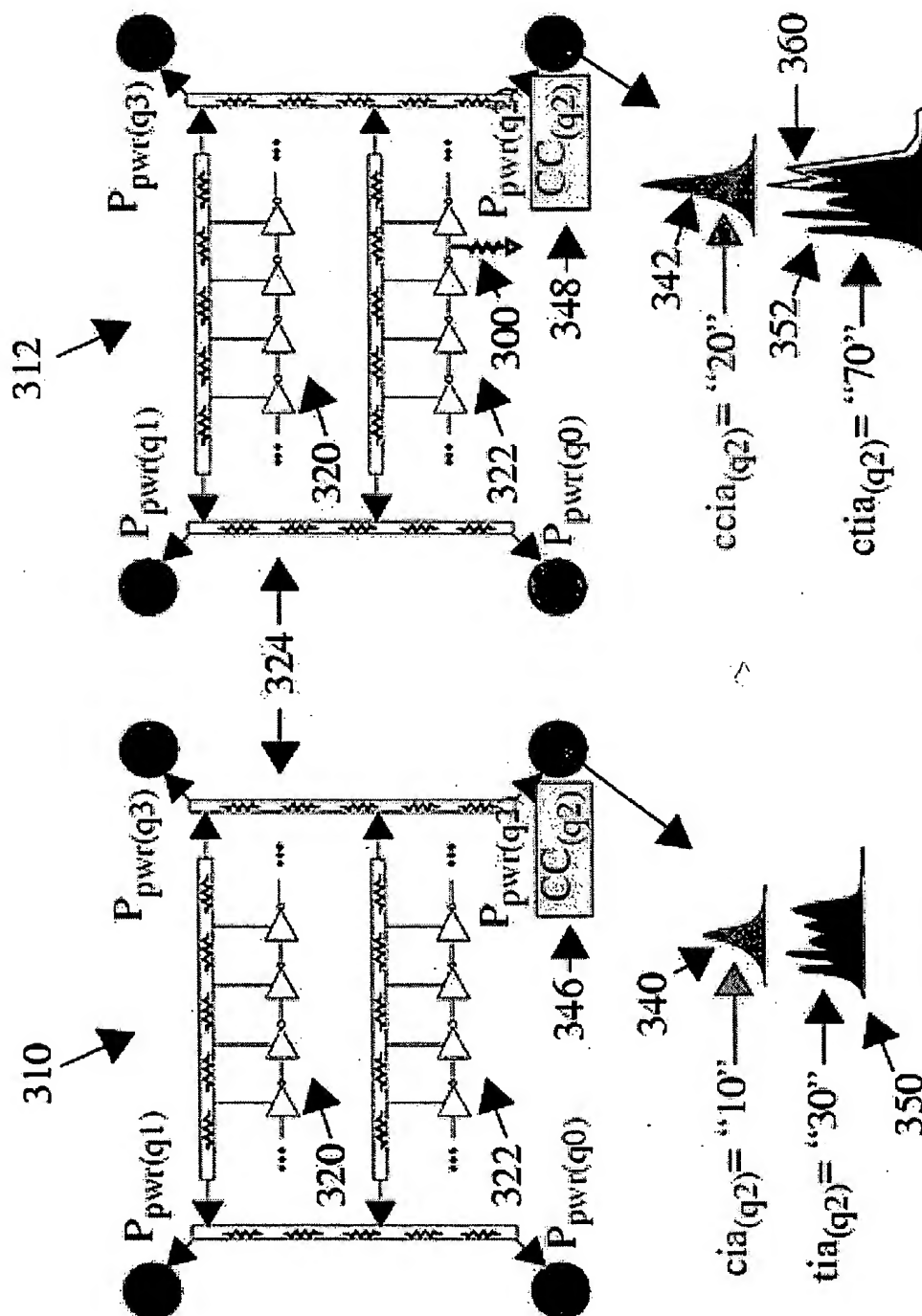


Figure 12